

# FDJ129P

# P-Channel -2.5 Vgs Specified PowerTrench<sup>O</sup> MOSFET

## **General Description**

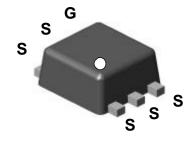
This P-Channel -2.5V specified MOSFET uses Fairchild's advanced low voltage PowerTrench process. It has been optimized for battery power management applications.

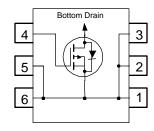
## **Applications**

- · Battery management
- Load switch

### **Features**

- -4.2 A, -20 V.  $R_{DS(ON)} = 70 \text{ m}\Omega$  @  $V_{GS} = -4.5 \text{ V}$  $R_{DS(ON)} = 120 \text{ m}\Omega$  @  $V_{GS} = -2.5 \text{ V}$
- Low gate charge
- High performance trench technology for extremely low Research.
- Compact industry standard SC75-6 surface mount package





## Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		-20	V
V <sub>GSS</sub>	Gate-Source Voltage		± 12	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	-4.2	Α
	– Pulsed	•	-16	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	1.6	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature	Range	-55 to +150	°C

## **Thermal Characteristics**

Rela	Thermal Resistance, Junction-to-Ambient	(Note 1a)	77	°C/W

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
.A	FDJ129P	7"	8mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	1	ı		<u> </u>	
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = -250 \mu\text{A}$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}$ , Referenced to $25^{\circ}\text{C}$		-18		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V},  V_{GS} = 0 \text{ V}$			-1	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	$V_{GS} = 12 \text{ V},  V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V},  V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-0.6	-1.1	-1.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}$ , Referenced to $25^{\circ}\text{C}$		3		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = -4.5 \text{ V}, \ I_D = -4.2 \text{ A}$ $V_{GS} = -2.5 \text{ V}, \ I_D = -3.3 \text{ A}$ $V_{GS} = -4.5 \text{ V}, \ I_D = -4.2, T_J = 125^{\circ}\text{C}$		54 91 72	70 120 100	mΩ
I <sub>D(on)</sub>	On–State Drain Current	$V_{GS} = -4.5 \text{ V}, \ V_{DS} = -5 \text{ V}$	-8			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 \text{ V},  I_{D} = -4.2 \text{ A}$		11		S
Dynamic	Characteristics			•	•	
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -10 \text{ V},  V_{GS} = 0 \text{ V},$		585		pF
Coss	Output Capacitance	f = 1.0 MHz		124		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	]		61		pF
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = -10 \text{ V},  I_{D} = -1 \text{ A},$		10	20	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V},  R_{GEN} = 6 \Omega$		9	18	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	1		17	30	ns
t <sub>f</sub>	Turn-Off Fall Time	1		10	20	ns
Qg	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -4.2 \text{ A},$		4	6	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = -4.5 V		1.1		nC
$Q_{gd}$	Gate-Drain Charge			1.2		nC
Drain-So	ource Diode Characteristics a	nd Maximum Ratings				
V <sub>SD</sub>	Drain-Source Diode Forwar Voltage	$V_{GS} = 0 \text{ V},  I_S = -1.5 \text{ A}  \text{(Note 2)}$		-0.7	-1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	$I_F = -4.2 \text{ A},$		16		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$		13		nC

#### Notes

1. R<sub>8JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>8JC</sub> is guaranteed by design while R<sub>8CA</sub> is determined by the user's board design.



a) 77°C/W when mounted on a 1in² pad of 2 oz copper.



b) 115°C/W when mounted on a minimum pad of 2 oz copper.

Scale 1:1 on letter size paper

**2.** Pulse Test: Pulse Width <  $300\mu$ s, Duty Cycle < 2.0%

# **Typical Characteristics**

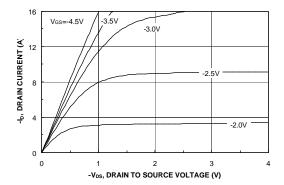


Figure 1. On-Region Characteristics.

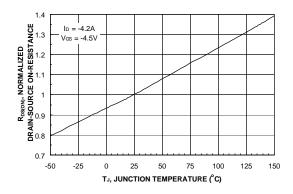


Figure 3. On-Resistance Variation withTemperature.

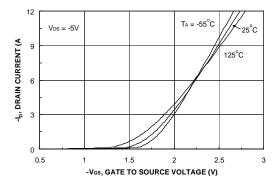


Figure 5. Transfer Characteristics.

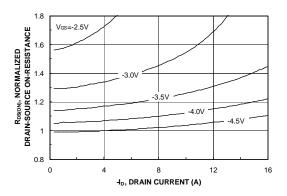


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

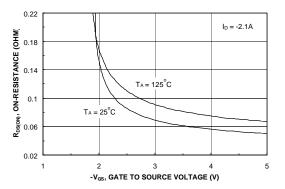


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

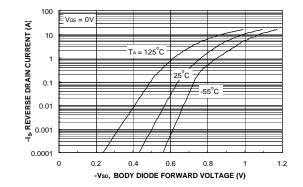
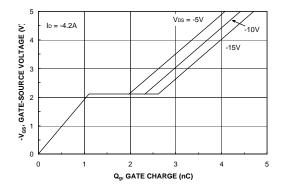


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**



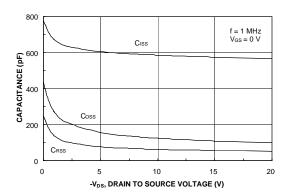
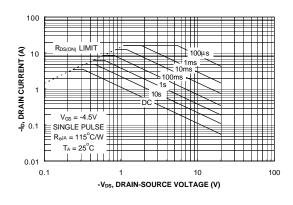


Figure 7. Gate Charge Characteristics.





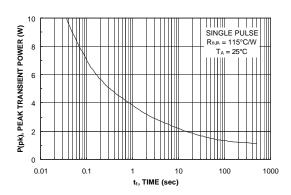


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

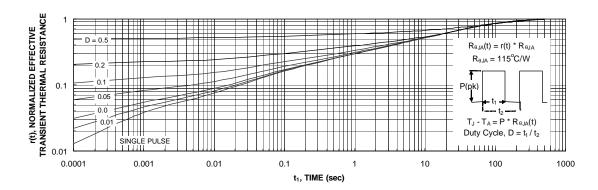


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient themal response will change depending on the circuit board design.

# **Dimensional Outline and Pad Layout** PKG A Œ PKG 0.30 MIN-Œ 6 DRAIN TERMINAL 2.35 MIN PKG Q PKG Q 0.90 1.35 0.50 MIN 3 3 0.275 0.125 1 (0.20)0.50 **⊕** 0.075 AB **-**1.00 <del>-</del> 0.50 LAND PATTERN RECOMMENDATION 1.00 PKG PKG Œ Œ 0.225 0.075 0.80 0.65 П 1.075 0.925 SEATING PLANE PKG (0.24)DRAIN √<sup>(0.18)</sup> 3 NOTES: UNLESS OTHERWISE SPECIFIED NO PACKAGE STANDARD REFERENCE AS OF JULY 13, 2000. ALL DIMENSIONS ARE IN MILLIMETERS. DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. PKG Q (0.75)(1.20)**BOTTOM VIEW**

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